

# CDx4HC112、CDx4HCT112 デュアル J-K フリップ・フロップ、 ネガティブ・エッジ・トリガのセット/リセット付き

## 1 特長

- クロック入力にヒステリシスを備えることで、ノイズ耐性を向上させ、立ち上がり/立ち下がり時間が大きい入力にも対応
- 非同期のセット/リセット
- 相補出力
- バッファ付き入力
- $f_{MAX} = 60\text{MHz}$  (標準値、 $V_{CC} = 5\text{V}$ 、 $C_L = 15\text{pF}$ 、 $T_A = 25^\circ\text{C}$ )
- ファンアウト (全温度範囲にわたって)
  - 標準出力: 10 個の LSTTL 負荷
  - バス・ドライバ出力: 15 個の LSTTL 負荷
- 広い動作温度範囲:  $-55^\circ\text{C} \sim 125^\circ\text{C}$
- 平衡な伝搬遅延と遷移時間
- LSTTL ロジック IC に比べて消費電力を大幅削減
- HC タイプ
  - 2V~6V で動作
  - 優れたノイズ耐性:  $V_{CC}$  に対して  $N_{IL} = 30\%$ 、 $N_{IH} = 30\%$  ( $V_{CC} = 5\text{V}$  時)
- HCT タイプ
  - 4.5V~5.5V で動作
  - LSTTL 入力ロジックと直接互換、 $V_{IL} = 0.8\text{V}$  (最大値)、 $V_{IH} = 2\text{V}$  (最小値)
  - CMOS 入力互換、 $V_{OL}$ 、 $V_{OH}$  で  $I_L \leq 1\mu\text{A}$

## 2 概要

'HC112 および 'HCT112 はシリコンゲート CMOS 技術を使用して、LSTTL 部品と同等の動作速度を実現しています。これらのデバイスは、標準 CMOS IC の低消費電力と、10 個の LSTTL 負荷に耐える駆動能力とを合わせ持っています。

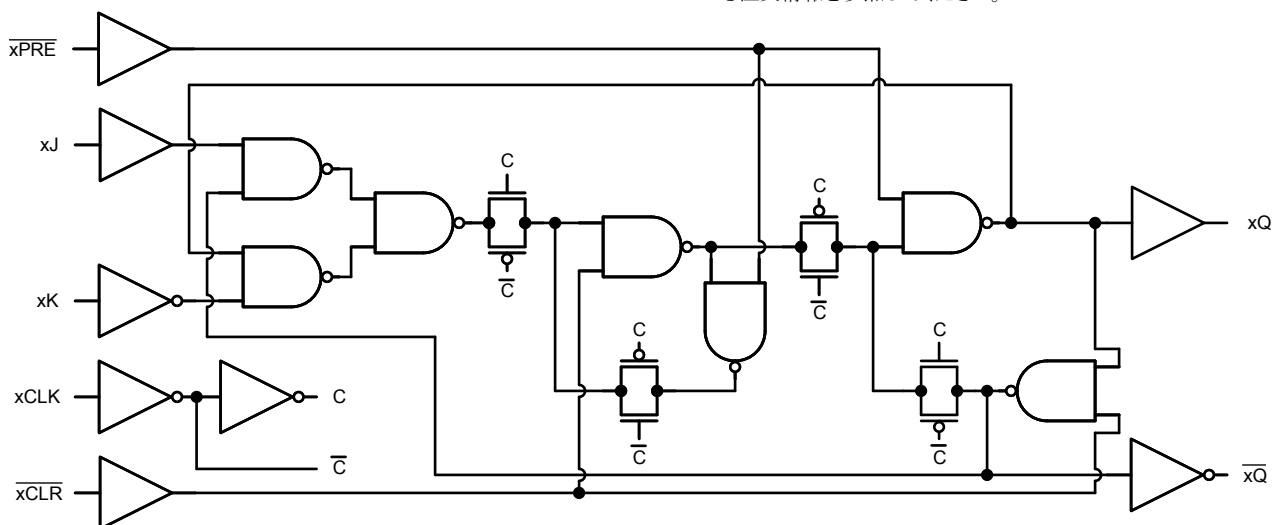
これらのフリップ・フロップは、独立した J、K、 $\overline{\text{PRE}}$ 、 $\overline{\text{CLR}}$ 、クロック入力と Q および  $\overline{\text{Q}}$  の各出力を備えています。これらは、クロック・パルスが負方向に遷移する時に状態が変化します。 $\overline{\text{PRE}}$  と  $\overline{\text{CLR}}$  は、低レベル入力によって非同期で行われます。

HCT ロジック・ファミリの機能およびピン配置は、標準の LS ロジック・ファミリと互換です。

### パッケージ情報

部品番号	パッケージ <sup>(1)</sup>	本体サイズ (公称)
CD54HC112F3A	CDIP (16)	24.38mm × 6.92mm
CD74HC112M96	SOIC (16)	9.90mm × 3.90mm
CD74HC112E	PDIP (16)	19.31mm × 6.35mm
CD74HCT112E	PDIP (16)	19.31mm × 6.35mm
CD74HC112NSR	SO (16)	6.20mm × 5.30mm
CD74HC112PW	TSSOP (16)	5.00mm × 4.40mm

(1) 利用可能なパッケージについては、このデータシートの末尾にある注文情報を参照してください。



機能ダイアグラム



## Table of Contents

<b>1 特長</b> .....	1	7.2 Functional Block Diagram.....	10
<b>2 概要</b> .....	1	7.3 Device Functional Modes.....	10
<b>3 Revision History</b> .....	2	<b>8 Power Supply Recommendations</b> .....	11
<b>4 Pin Configuration and Functions</b> .....	3	<b>9 Layout</b> .....	11
<b>5 Specifications</b> .....	4	9.1 Layout Guidelines.....	11
5.1 Absolute Maximum Ratings.....	4	<b>10 Device and Documentation Support</b> .....	12
5.2 Recommended Operating Conditions.....	4	10.1 Receiving Notification of Documentation Updates..	12
5.3 Thermal Information.....	4	10.2 サポート・リソース.....	12
5.4 Electrical Characteristics.....	5	10.3 Trademarks.....	12
5.5 Prerequisite for Switching Characteristics.....	6	10.4 Electrostatic Discharge Caution.....	12
5.6 Switching Characteristics.....	7	10.5 Glossary.....	12
<b>6 Parameter Measurement Information</b> .....	8	<b>11 Mechanical, Packaging, and Orderable Information</b> .....	12
<b>7 Detailed Description</b> .....	10		
7.1 Overview.....	10		

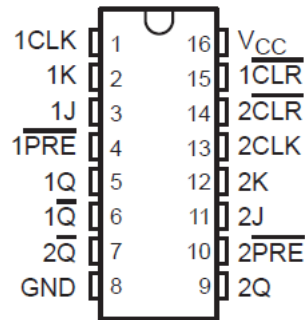
### 3 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

<b>Changes from Revision I (January 2022) to Revision J (October 2022)</b>	<b>Page</b>
• Increased R $\theta$ JA for packages: D (73 to 117.2); N (67 to 69.3); NS (64 to 88.4); PW (108 to 137.5).....	4

<b>Changes from Revision H (October 2003) to Revision I (January 2022)</b>	<b>Page</b>
• 最新のデータシート規格を反映するように、文書全体の採番、書式設定、表、図、相互参照を更新.....	1
• Updated pin names to match current standards. $\overline{CP}$ is now CLK; $\overline{S}$ is now PRE; $\overline{1R}$ is now $\overline{1CLR}$ ; $\overline{2R}$ is now $\overline{2CLR}$ ; $\overline{2CP}$ is now $\overline{2CLK}$ ; $\overline{2S}$ is now $\overline{2PRE}$ .....	3

## 4 Pin Configuration and Functions



**J, N, D, NS, or PW package**  
**16-Pin CDIP, PDIP, SOIC, SO, TSSOP**  
**Top View**

## 5 Specifications

### 5.1 Absolute Maximum Ratings

(1)			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		-0.5	7	V
I <sub>IK</sub>	Input diode current	For V <sub>I</sub> < -0.5 V or V <sub>I</sub> > V <sub>CC</sub> + 0.5 V		± 20	mA
I <sub>O</sub>	Drain current, per output	For -0.5 V < V <sub>O</sub> < V <sub>CC</sub> + 0.5 V		± 25	mA
I <sub>OK</sub>	Output diode current	For V <sub>O</sub> < -0.5 V or V <sub>O</sub> > V <sub>CC</sub> + 0.5 V		± 20	mA
I <sub>O</sub>	Output source or sink current per output pin	For V <sub>O</sub> > -0.5 V or V <sub>O</sub> < V <sub>CC</sub> + 0.5 V		± 25	mA
I <sub>CC</sub>	Continuous current through V <sub>CC</sub> or GND			± 50	mA
T <sub>J</sub>	Junction temperature			150	°C
T <sub>stg</sub>	Storage temperature range		-65	150	°C
	Lead temperature (Soldering 10s)			300	°C

(1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 5.2 Recommended Operating Conditions

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range	HC types	2	6	V
		HCT types	4.5	5.5	
V <sub>I</sub> , V <sub>O</sub>	Input or output voltage		0	V <sub>CC</sub>	V
t <sub>r</sub> , t <sub>f</sub>	Input rise and fall time	2 V		1	ms
		4.5 V		1	
		6 V		1	
T <sub>A</sub>	Temperature range		-55	125	°C

### 5.3 Thermal Information

THERMAL METRIC		D (SOIC)	N (PDIP)	NS (SO)	PW (TSSOP)	UNIT
		16 PINS	16 PINS	16 PINS	16 PINS	
R <sub>θJA</sub>	Junction-to-ambient thermal resistance <sup>(1)</sup>	117.2	69.3	88.4	137.5	°C/W
R <sub>θJC (top)</sub>	Junction-to-case (top) thermal resistance	77.2	61.8	46	75.3	°C/W
R <sub>θJB</sub>	Junction-to-board thermal resistance	75.6	49.3	50.6	82.2	°C/W
Ψ <sub>JT</sub>	Junction-to-top characterization parameter	38.1	34.6	13	25.1	°C/W
Ψ <sub>JB</sub>	Junction-to-board characterization parameter	75.3	49	50.2	81.8	°C/W
R <sub>θJC (bot)</sub>	Junction-to-case (bottom) thermal resistance	N/A	N/A	N/A	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC package thermal metrics](#) application report.

## 5.4 Electrical Characteristics

PARAMETER	TEST CONDITIONS <sup>(2)</sup>	V <sub>CC</sub> (V)	25°C			–40°C to 85°C		–55°C to 125°C		UNIT	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX		
<b>HC TYPES</b>											
V <sub>IH</sub>	High level input voltage		2	1.5		1.5		1.5		V	
			4.5	3.15		3.15		3.15			
			6	4.2		4.2		4.2			
V <sub>IL</sub>	Low level input voltage		2		0.5		0.5		0.5	V	
			4.5		1.35		1.35		1.35		
			6		1.8		1.8		1.8		
V <sub>OH</sub>	High level output voltage	I <sub>OH</sub> = – 20 μA	2	1.9		1.9		1.9		V	
			4.5	4.4		4.4		4.4			
			6	5.9		5.9		5.9			
	High level output voltage	I <sub>OH</sub> = – 4 mA	4.5	3.98		3.84		3.7			
			I <sub>OH</sub> = – 5.2 mA	6	5.48		5.34		5.2		
V <sub>OL</sub>	Low level output voltage	I <sub>OL</sub> = 20 μA		2		0.1		0.1		V	
			4.5		0.1		0.1		0.1		
			6		0.1		0.1		0.1		
	Low level output voltage	I <sub>OL</sub> = 4 mA	4.5		0.26		0.33		0.4		
			I <sub>OL</sub> = 5.2 mA	6		0.26		0.33			0.4
I <sub>I</sub>	Input leakage current	V <sub>CC</sub> or GND		6		±0.1		±1		±1	μA
I <sub>CC</sub>	Supply current	V <sub>CC</sub> or GND	6		4		40		80	μA	
<b>HCT TYPES</b>											
V <sub>IH</sub>	High level input voltage		4.5 to 5.5	2			2		2	V	
V <sub>IL</sub>	Low level input voltage		4.5 to 5.5		0.8		0.8		0.8	V	
V <sub>OH</sub>	High level output voltage	I <sub>OH</sub> = – 20 μA	4.5	4.4		4.4		4.4		V	
	High level output voltage	I <sub>OH</sub> = – 4 mA	4.5	3.98		3.84		3.7			
V <sub>OL</sub>	Low level output voltage	I <sub>OL</sub> = 20 μA	4.5		0.1		0.1		0.1	V	
	Low level output voltage	I <sub>OL</sub> = 4 mA	4.5		0.26		0.33		0.4		
I <sub>I</sub>	Input leakage current	V <sub>CC</sub> and GND	5.5		±0.1		±1		±1	μA	
I <sub>CC</sub>	Supply current	V <sub>CC</sub> and GND	5.5		4		40		80	μA	
ΔI <sub>CC</sub> <sup>(1)</sup>	Additional supply current per input pin	1PRE, 2PRE inputs held at V <sub>CC</sub> -2.1	4.5 to 5.5		100	180		225		245	μA
		1K, 2K inputs held at V <sub>CC</sub> -2.1	4.5 to 5.5		100	216		270		294	μA
		1CLR, 2CLR inputs held at V <sub>CC</sub> -2.1	4.5 to 5.5		100	234		292.5		318.5	μA
		1J, 2J, 1CLK, 2CLK inputs held at V <sub>CC</sub> -2.1	4.5 to 5.5		100	360		450		490	μA

(1) For dual-supply systems theoretical worst case (V<sub>I</sub> = 2.4 V, V<sub>CC</sub> = 5.5 V) specification is 1.8 mA.

(2)  $V_I = V_{IH}$  or  $V_{IL}$ , unless otherwise noted.

### 5.5 Prerequisite for Switching Characteristics

PARAMETER		V <sub>CC</sub> (V)	25°C			–40°C to 85°C		–55°C to 125°C		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<b>HC TYPES</b>										
t <sub>W</sub>	Pulse width CLK	2	80			100		120		ns
		4.5	16			20		24		
		6	14			17		20		
t <sub>W</sub>	Pulse width $\overline{\text{CLR}}$ , $\overline{\text{PRE}}$	2	80			100		120		ns
		4.5	16			20		24		
		6	14			17		20		
t <sub>SU</sub>	Setup time J, K, to CLK	2	80			100		120		ns
		4.5	16			20		24		
		6	14			17		20		
t <sub>H</sub>	Hold time J, K, to CLK	2	0			0		0		ns
		4.5	0			0		0		
		6	0			0		0		
t <sub>REM</sub>	Removal time $\overline{\text{CLR}}$ to CLK, $\overline{\text{PRE}}$ to CLK	2	80			100		120		ns
		4.5	16			20		24		
		6	14			17		20		
f <sub>MAX</sub>	CLK frequency	2	6			5		4		MHz
		4.5	30			25		20		
		6	35			29		23		
<b>HCT TYPES</b>										
t <sub>SU</sub>	Pulse width CLK	4.5	16			20		24		ns
t <sub>W</sub>	Pulse width $\overline{\text{CLR}}$ , $\overline{\text{PRE}}$	4.5	18			23		27		ns
t <sub>H</sub>	Setup time J, K, to CLK	4.5	16			20		24		ns
t <sub>REM</sub>	Hold time J, K, to CLK	4.5	3			3		3		ns
t <sub>W</sub>	Removal time $\overline{\text{CLR}}$ to CLK, $\overline{\text{PRE}}$ to CLK	4.5	20			25		30		ns
f <sub>MAX</sub>	CLK frequency	4.5	30			25		20		MHz

## 5.6 Switching Characteristics

 $t_r, t_f = 6 \text{ ns}$ 

PARAMETER	V <sub>CC</sub> (V)	25°C			–40°C to 85°C		–55°C to 125°C		UNIT	
		MIN	TYP	MAX	MIN	MAX	MIN	MAX		
<b>HC TYPES</b>										
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay, CLK to Q, $\bar{Q}$	2		175		220		265	ns	
		4.5		14 <sup>(3)</sup>	35		44	53		
		6			30		37	45		
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay, PRE to Q, $\bar{Q}$	2		155		195		235	ns	
		4.5		13 <sup>(3)</sup>	31		39	47		
		6			26		33	40		
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay, CLR to Q, $\bar{Q}$	2		180		225		270	ns	
		4.5		15 <sup>(3)</sup>	36		45	54		
		6			31		38	46		
t <sub>TLH</sub> , t <sub>THL</sub>	Output transition time	2		75		95		110	ns	
		4.5		15		19		22		
		6		13		16		19		
C <sub>I</sub>	Input capacitance			10		10		10	pF	
f <sub>MAX</sub>	CLK frequency	5		60 <sup>(3)</sup>					MHz	
C <sub>PD</sub>	Power dissipation capacitance <sup>(1) (2)</sup>	5		12 <sup>(4)</sup>					pF	
<b>HCT TYPES</b>										
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay, CLK to Q, $\bar{Q}$	4.5		14 <sup>(3)</sup>	35		44		53	ns
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay, PRE to Q, $\bar{Q}$	4.5		13 <sup>(3)</sup>	32		40		48	ns
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay, CLR to Q, $\bar{Q}$	4.5		14 <sup>(3)</sup>	37		46		56	ns
t <sub>TLH</sub> , t <sub>THL</sub>	Output transition time	4.5		15		19		22	ns	
C <sub>I</sub>	Input capacitance			10		10		10	pF	
f <sub>MAX</sub>	CLK frequency	5		60 <sup>(3)</sup>					MHz	
C <sub>PD</sub>	Power dissipation capacitance <sup>(1) (2)</sup>	5		20 <sup>(4)</sup>					pF	

(1) C<sub>PD</sub> is used to determine the dynamic power consumption, per flip-flop.

(2) P<sub>D</sub> = C<sub>PD</sub> V<sub>CC</sub><sup>2</sup> f<sub>i</sub> + ∑ C<sub>L</sub> f<sub>o</sub> where f<sub>i</sub> = input frequency, f<sub>o</sub> = output frequency, C<sub>L</sub> = output load capacitance, V<sub>CC</sub> = supply voltage.

(3) C<sub>L</sub> = 15 pF and V<sub>CC</sub> = 5 V.

(4) V<sub>CC</sub> = 5 V.

## 6 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 1 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_t < 6 \text{ ns}$ .

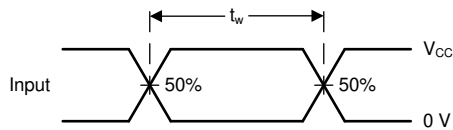
For clock inputs,  $f_{\text{max}}$  is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.

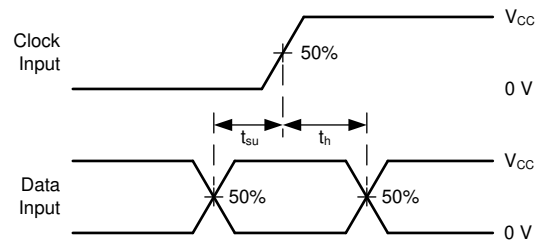


(1)  $C_L$  includes probe and test-fixture capacitance.

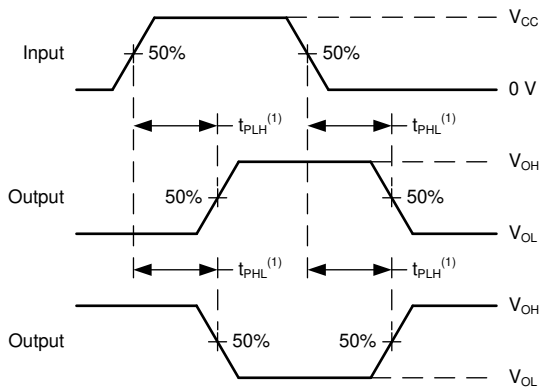
**6-1. Load Circuit for Push-Pull Outputs**



**6-2. Voltage Waveforms, Standard CMOS Inputs Pulse Duration**

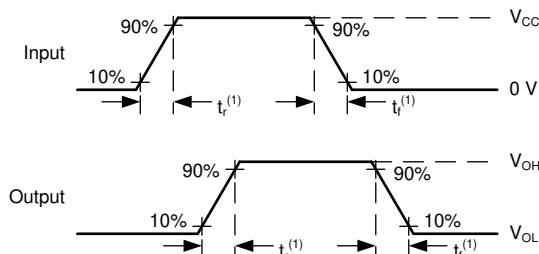


**6-3. Voltage Waveforms, Standard CMOS Inputs Setup and Hold Times**



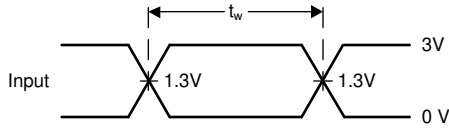
(1) The greater between  $t_{\text{PLH}}$  and  $t_{\text{PHL}}$  is the same as  $t_{\text{pd}}$ .

**6-4. Voltage Waveforms, Propagation Delays for Standard CMOS Inputs**

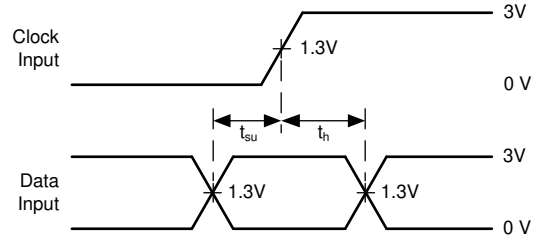


(1) The greater between  $t_r$  and  $t_f$  is the same as  $t_t$ .

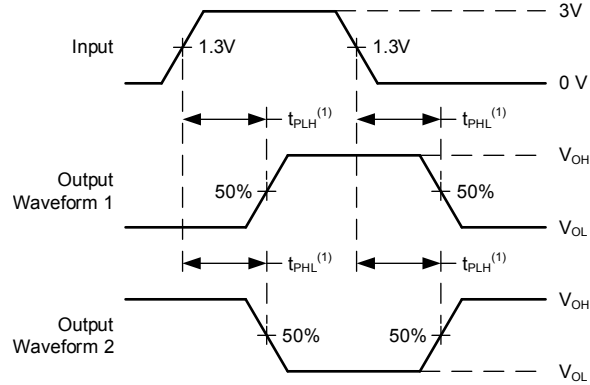
**6-5. Voltage Waveforms, Input and Output Transition Times for Standard CMOS Inputs**



**6-6. Voltage Waveforms, TTL-Compatible CMOS Inputs Pulse Duration**



**6-7. Voltage Waveforms, TTL-Compatible CMOS Inputs Setup and Hold Times**



(1) The greater between  $t_{PLH}$  and  $t_{PHL}$  is the same as  $t_{pd}$ .

**6-8. Voltage Waveforms, Propagation Delays for TTL-Compatible Inputs**

## 7 Detailed Description

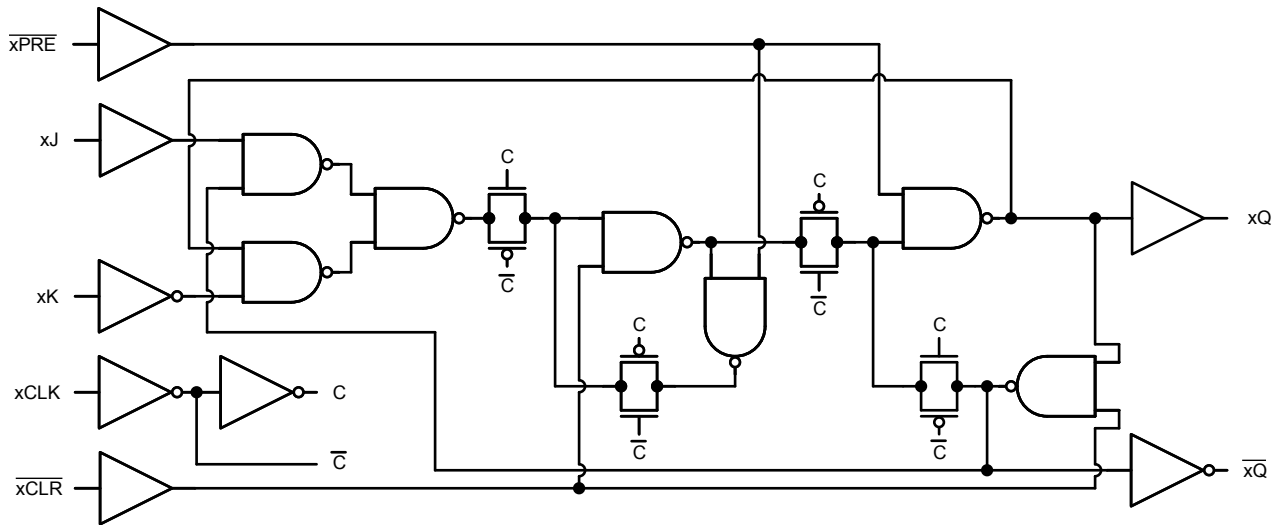
### 7.1 Overview

The 'HC112 and 'HCT112 utilize silicon-gate CMOS technology to achieve operating speeds equivalent to LSTTL parts. They exhibit the low power consumption of standard CMOS integrated circuits, together with the ability to drive 10 LSTTL loads.

These flip-flops have independent J, K,  $\overline{\text{PRE}}$ ,  $\overline{\text{CLR}}$ , and Clock inputs and Q and  $\overline{\text{Q}}$  outputs. They change state on the negative-going transition of the clock pulse.  $\overline{\text{PRE}}$  and  $\overline{\text{CLR}}$  are accomplished asynchronously by low-level inputs.

The HCT logic family is functionally and pin-compatible with the standard LS logic family.

### 7.2 Functional Block Diagram



### 7.3 Device Functional Modes

表 7-1. Truth Table<sup>(1)</sup>

INPUTS					OUTPUTS	
PRE	$\overline{\text{CLR}}$	CLK	J	K	Q	$\overline{\text{Q}}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H <sup>(2)</sup>	H <sup>(2)</sup>
H	H	–	L	L	No Change	
H	H	–	H	L	H	L
H	H	–	L	H	L	H
H	H	–	H	H	Toggle	
H	H	H	X	X	No Change	

- (1) H = high level (steady state), L = low level (steady state), X = don't care, ↓ = high-to-low transition  
 (2) Output states unpredictable if both  $\overline{\text{S}}$  and  $\overline{\text{R}}$  go high simultaneously after both being low at the same time.

## 8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- $\mu$ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

## 9 Layout

### 9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.

## 10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

### 10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com](http://ti.com). Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 10.2 サポート・リソース

TI E2E™ サポート・フォーラムは、エンジニアが検証済みの回答と設計に関するヒントをエキスパートから迅速かつ直接得ることができる場所です。既存の回答を検索したり、独自の質問をしたりすることで、設計に必要な支援を迅速に得ることができます。

リンクされているコンテンツは、該当する貢献者により、現状のまま提供されるものです。これらは TI の仕様を構成するものではなく、必ずしも TI の見解を反映したものではありません。TI の [使用条件](#) を参照してください。

### 10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

すべての商標は、それぞれの所有者に帰属します。

### 10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### 10.5 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

## 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

**PACKAGING INFORMATION**

Orderable part number	Status (1)	Material type (2)	Package   Pins	Package qty   Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
<a href="#">5962-8970201EA</a>	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-8970201EA CD54HCT112F3A
<a href="#">CD54HC112F3A</a>	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8408801EA CD54HC112F3A
CD54HC112F3A.A	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8408801EA CD54HC112F3A
<a href="#">CD54HCT112F3A</a>	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-8970201EA CD54HCT112F3A
CD54HCT112F3A.A	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-8970201EA CD54HCT112F3A
<a href="#">CD74HC112E</a>	Active	Production	PDIP (N)   16	25   TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HC112E
CD74HC112E.A	Active	Production	PDIP (N)   16	25   TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HC112E
<a href="#">CD74HC112M96</a>	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC112M
CD74HC112M96.A	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC112M
<a href="#">CD74HC112MT</a>	Obsolete	Production	SOIC (D)   16	-	-	Call TI	Call TI	-55 to 125	HC112M
<a href="#">CD74HC112NSR</a>	Active	Production	SOP (NS)   16	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC112M
CD74HC112NSR.A	Active	Production	SOP (NS)   16	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC112M
<a href="#">CD74HC112PW</a>	Obsolete	Production	TSSOP (PW)   16	-	-	Call TI	Call TI	-55 to 125	HJ112
<a href="#">CD74HC112PWR</a>	Active	Production	TSSOP (PW)   16	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ112
CD74HC112PWR.A	Active	Production	TSSOP (PW)   16	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ112
<a href="#">CD74HCT112E</a>	Active	Production	PDIP (N)   16	25   TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HCT112E
CD74HCT112E.A	Active	Production	PDIP (N)   16	25   TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HCT112E

(1) **Status:** For more details on status, see our [product life cycle](#).

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

**OTHER QUALIFIED VERSIONS OF CD54HC112, CD54HCT112, CD74HC112, CD74HCT112 :**

- Catalog : [CD74HC112](#), [CD74HCT112](#)
- Military : [CD54HC112](#), [CD54HCT112](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Military - QML certified for Military and Defense Applications

**TAPE AND REEL INFORMATION**

**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC112M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HC112NSR	SOP	NS	16	2000	330.0	16.4	8.1	10.4	2.5	12.0	16.0	Q1
CD74HC112PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HC112PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

**TAPE AND REEL BOX DIMENSIONS**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC112M96	SOIC	D	16	2500	340.5	336.1	32.0
CD74HC112NSR	SOP	NS	16	2000	353.0	353.0	32.0
CD74HC112PWR	TSSOP	PW	16	2000	353.0	353.0	32.0
CD74HC112PWR	TSSOP	PW	16	2000	353.0	353.0	32.0

**TUBE**


\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
CD74HC112E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC112E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC112E.A	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC112E.A	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT112E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT112E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT112E.A	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT112E.A	N	PDIP	16	25	506	13.97	11230	4.32



# PACKAGE OUTLINE

## NS0016A

### SOP - 2.00 mm max height

SOP



4220735/A 12/2021

#### NOTES:

1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.

# EXAMPLE BOARD LAYOUT

NS0016A

SOP - 2.00 mm max height

SOP



4220735/A 12/2021

NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

# EXAMPLE STENCIL DESIGN

NS0016A

SOP - 2.00 mm max height

SOP



SOLDER PASTE EXAMPLE  
BASED ON 0.125 mm THICK STENCIL  
SCALE:7X

4220735/A 12/2021

NOTES: (continued)

7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
8. Board assembly site may have different recommendations for stencil design.

D (R-PDSO-G16)

PLASTIC SMALL OUTLINE

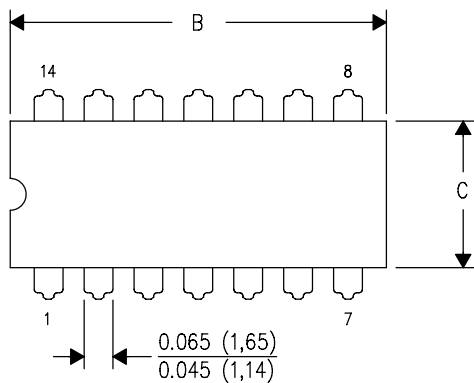


- NOTES:
- A. All linear dimensions are in inches (millimeters).
  - B. This drawing is subject to change without notice.
  - C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
  - D. Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
  - E. Reference JEDEC MS-012 variation AC.

J (R-GDIP-T\*\*)

14 LEADS SHOWN

CERAMIC DUAL IN-LINE PACKAGE



DIM \ PINS **	14	16	18	20
A	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC
B MAX	0.785 (19,94)	.840 (21,34)	0.960 (24,38)	1.060 (26,92)
B MIN	—	—	—	—
C MAX	0.300 (7,62)	0.300 (7,62)	0.310 (7,87)	0.300 (7,62)
C MIN	0.245 (6,22)	0.245 (6,22)	0.220 (5,59)	0.245 (6,22)



4040083/F 03/03

- NOTES:
- All linear dimensions are in inches (millimeters).
  - This drawing is subject to change without notice.
  - This package is hermetically sealed with a ceramic lid using glass frit.
  - Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
  - Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.



4220204/B 12/2023

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.

# EXAMPLE BOARD LAYOUT

PW0016A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE  
EXPOSED METAL SHOWN  
SCALE: 10X



SOLDER MASK DETAILS

4220204/B 12/2023

NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

# EXAMPLE STENCIL DESIGN

PW0016A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE  
BASED ON 0.125 mm THICK STENCIL  
SCALE: 10X

4220204/B 12/2023

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

N (R-PDIP-T\*\*)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



4040049/E 12/2002

- NOTES:
- A. All linear dimensions are in inches (millimeters).
  - B. This drawing is subject to change without notice.
  - (C) Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
  - (D) The 20 pin end lead shoulder width is a vendor option, either half or full width.

## 重要なお知らせと免責事項

TI は、技術データと信頼性データ(データシートを含みます)、設計リソース(リファレンス デザインを含みます)、アプリケーションや設計に関する各種アドバイス、Web ツール、安全性情報、その他のリソースを、欠陥が存在する可能性のある「現状のまま」提供しており、商品性および特定目的に対する適合性の黙示保証、第三者の知的財産権の非侵害保証を含むいかなる保証も、明示的または黙示的にかかわらず拒否します。

これらのリソースは、TI 製品を使用する設計の経験を積んだ開発者への提供を意図したものです。(1) お客様のアプリケーションに適した TI 製品の選定、(2) お客様のアプリケーションの設計、検証、試験、(3) お客様のアプリケーションに該当する各種規格や、その他のあらゆる安全性、セキュリティ、規制、または他の要件への確実な適合に関する責任を、お客様のみが単独で負うものとし、

上記の各種リソースは、予告なく変更される可能性があります。これらのリソースは、リソースで説明されている TI 製品を使用するアプリケーションの開発の目的でのみ、TI はその使用をお客様に許諾します。これらのリソースに関して、他の目的で複製することや掲載することは禁止されています。TI や第三者の知的財産権のライセンスが付与されている訳ではありません。お客様は、これらのリソースを自身で使用した結果発生するあらゆる申し立て、損害、費用、損失、責任について、TI およびその代理人を完全に補償するものとし、TI は一切の責任を拒否します。

TI の製品は、[TI の販売条件](#)、[TI の総合的な品質ガイドライン](#)、[ti.com](#) または TI 製品などに関連して提供される他の適用条件に従い提供されます。TI がこれらのリソースを提供することは、適用される TI の保証または他の保証の放棄の拡大や変更を意味するものではありません。TI がカスタム、またはカスタマー仕様として明示的に指定していない限り、TI の製品は標準的なカタログに掲載される汎用機器です。

お客様がいかなる追加条項または代替条項を提案する場合も、TI はそれらに異議を唱え、拒否します。

Copyright © 2026, Texas Instruments Incorporated

最終更新日 : 2025 年 10 月